Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10566937	OSWALD ET AL.
Examiner	Art Unit
Irina Krylova	1796

SEARCHED					
Class	Subclass	Date	Examiner		
525	240	09/17/09	IK		
526	352	09/17/09	IK		
525	240, 191	05/04/10	IK		
526	352, 352.2	05/04/10	IK		
264	176.1	05/07/10	IK		

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search in EAST and eDAN was conducted	09/17/09	IK
Searched key words:"ethylene, polyethylene, linear, branch\$, regression, modulus, slope, CDF, melt index, melt flow, melt strength, rheolog\$"	09/17/09	IK
Search by STIC was conducted	09/17/09	IK
Searched key words: "ethylene, polyethylene, lelt index, MFR, MI, melt flow, MWD, distribution, molecular weight, loss modulus, storage modulus"	05/04/10	IK

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
525	240, 191	05/04/10	IK	
526	352.2, 352	05/04/10	IK	
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